Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,091	OYABE ET AL.	
Examiner	Art Unit	
Thomas H. Parsons	1745	

	SEARCHED		
Class	Subclass	Date	Examiner
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· INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Name Search	3/13/2006	ТНР
East (USPAT) - search history printout	3/13/2006	ТНР
Weat (EPAB, JPAB, DWPI, TDBD) - see search history printout	3/13/2006	THP
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